Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/016,199	BEAN ET AL.
Examiner	Art Unit

2612

James M. Hannett

SEARCHED					
Class	Subclass	Date	Examiner		
714	22	6/22/2005	JMH		
348	372	6/22/2005	ЈМН		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH (INCLUDING SEAR)
	DATE	EXMR
East	6/22/2005	ЈМН